

Notice of References Cited

Application/Control No.

10/533,860

Applicant(s)/Patent Under
Reexamination
TOUCHAIS ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 1 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,291,277 A	09-1981	Davis et al.	330/149
*	B	US-4,700,151 A	10-1987	Nagata, Yoshinori	332/123
*	C	US-5,049,832 A	09-1991	Cavers, James K.	330/149
*	D	US-5,148,448 A	09-1992	Karam et al.	375/298
*	E	US-5,507,014 A	04-1996	Wray et al.	455/114.3
*	F	US-5,559,807 A	09-1996	van den Heuvel et al.	370/347
*	G	US-5,699,383 A	12-1997	Ichiyoshi, Osamu	375/297
*	H	US-5,732,333 A	03-1998	Cox et al.	455/126
*	I	US-5,748,678 A	05-1998	Valentine et al.	375/297
*	J	US-5,760,646 A	06-1998	Belcher et al.	330/149
*	K	US-5,867,065 A	02-1999	Leyendecker, Robert Richard	330/149
*	L	US-5,892,397 A	04-1999	Belcher et al.	330/149
*	M	US-5,913,172 A	06-1999	McCabe et al.	455/503

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/533,860

Applicant(s)/Patent Under
Reexamination
TOUCHAIS ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 2 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,929,703 A	07-1999	Sehier et al.	330/149
*	B	US-5,920,808 A	07-1999	Jones et al.	455/127.1
*	C	US-5,923,712 A	07-1999	Leyendecker et al.	375/297
*	D	US-5,959,499 A	09-1999	Khan et al.	330/149
*	E	US-5,959,500 A	09-1999	Garrido, Armando Cova	330/151
*	F	US-6,043,707 A	03-2000	Budnik, Brian Joseph	330/10
*	G	US-6,075,411 A	06-2000	Briffa et al.	330/149
*	H	US-6,141,390 A	10-2000	Cova, Armando	375/297
*	I	US-6,320,463 B1	11-2001	Leva et al.	330/149
*	J	US-2002/0016154 A1	02-2002	Huttunen, Mikko	455/63
*	K	US-6,369,648 B1	04-2002	Kirkman, George F.	330/43
*	L	US-6,396,350 B2	05-2002	Nam, Ki Y.	330/297
*	M	US-2002/0171485 A1	11-2002	Cova, Armando C.	330/149

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/533,860

Applicant(s)/Patent Under
Reexamination
TOUCHAIS ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 3 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0035494 A1	02-2003	Bauder et al.	375/296
*	B	US-2003/0031270 A1	02-2003	Giardina et al.	375/296
*	C	US-2003/0072388 A1	04-2003	Francos et al.	375/296
*	D	US-2003/0063686 A1	04-2003	Giardina et al.	375/296
*	E	US-2003/0146787 A1	08-2003	Hedberg et al.	330/149
*	F	US-2003/0156657 A1	08-2003	Schrader et al.	375/295
*	G	US-2003/0156658 A1	08-2003	Dartois, Luc	375/297
*	H	US-2003/0179830 A1	09-2003	Eidson et al.	375/296
*	I	US-2003/0197558 A1	10-2003	Bauder et al.	330/149
*	J	US-2003/0184374 A1	10-2003	Huang et al.	330/149
*	K	US-2003/0207680 A1	11-2003	Yang et al.	455/341
*	L	US-6,674,808 B1	01-2004	Griph et al.	375/285
*	M	US-6,680,649 B2	01-2004	Rydin, Arne	330/149

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/533,860

Applicant(s)/Patent Under
Reexamination
TOUCHAIS ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 4 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0028146 A1	02-2004	Winkler, Clive	375/260
*	B	US-2004/0057533 A1	03-2004	Kermalli, Munawar Hussein	375/296
*	C	US-6,731,168 B2	05-2004	Hedberg et al.	330/149
*	D	US-6,741,662 B1	05-2004	Francos et al.	375/297
*	E	US-6,771,708 B1	08-2004	Suga et al.	375/278
*	F	US-6,853,246 B2	02-2005	Bauder et al.	330/149
*	G	US-2005/0032472 A1	02-2005	Jiang et al.	455/013.4
*	H	US-6,885,241 B2	04-2005	Huang et al.	330/149
*	I	US-6,891,902 B2	05-2005	Talwar et al.	375/296
*	J	US-2005/0163250 A1	07-2005	McCallister, Ronald Duane	375/296
*	K	US-2005/0163251 A1	07-2005	McCallister, Ronald Duane	375/296
*	L	US-2005/0169411 A1	08-2005	Kroeger, Brian William	375/350
*	M	US-6,931,080 B2	08-2005	Giardina et al.	375/296

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/533,860

Applicant(s)/Patent Under
Reexamination
TOUCHAIS ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 5 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,928,122 B2	08-2005	Opas et al.	375/296
*	B	US-2005/0231279 A1	10-2005	Moffatt et al.	330/149
*	C	US-6,985,704 B2	01-2006	Yang et al.	455/126
*	D	US-2006/0008028 A1	01-2006	Maltsev et al.	375/297
*	E	US-7,003,051 B2	02-2006	Francos et al.	375/296
*	F	US-2006/0039498 A1	02-2006	de Figueiredo et al.	375/297
*	G	US-7,016,431 B2	03-2006	Schrader et al.	375/297
*	H	US-7,062,233 B2	06-2006	Huttunen, Mikko	455/114.3
*	I	US-7,099,399 B2	08-2006	McCallister, Ronald Duane	375/269
*	J	US-7,085,330 B1	08-2006	Shirali, Kedar	375/296
*	K	US-2006/0247898 A1	11-2006	Cha, Sung-Keun	702/188
*	L	US-7,289,773 B2	10-2007	Braithwaite, Richard Neil	455/91
*	M	US-7,295,815 B1	11-2007	Wright et al.	455/91

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/533,860

Applicant(s)/Patent Under
Reexamination
TOUCHAIS ET AL.

Examiner

Jason M. Perilla

Art Unit

2611

Page 6 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,312,656 B2	12-2007	Saed, Aryan	330/149
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.